

Additive Manufacturing for Embedded Microelectronics

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Outline

- Introduction
 - Embedded Electronics
 - Additively Manufactured Electronics
 - Embedded Additively Manufactured Electronics
- Utilized Capabilities
- Studied Sensor
 - Sensor Details
 - Sensor Curing Profile
 - Sensor Properties and Performance
- Reflection
- Future Steps Toward Implementation
- Conclusion

Introduction to Embedded Electronics

- Embedding Electronics and Sensors Allows Them to be Placed at Critical Points
 - Not Limited To Available Surface Space
- Uses
 - Monitoring of Critical Load Bearing Structures
 - Bridge Supports
 - Aircraft Joints
 - Ship Hulls
 - Monitoring of Devices Subject to Extreme Environments
 - Unmanned Probes
 - Turbine Blades
- Embedding Strategies
 - Pause of Print Insertion



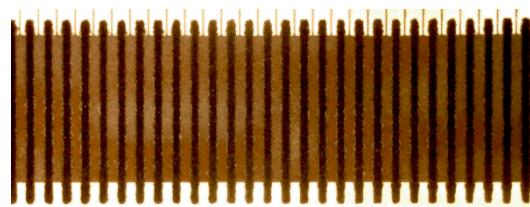
[1]

[1] M. Leu, et. al, Missouri S&T, 2015

Additively Manufactured (AM) Electronics

- Circuit Components

- Resistors



Series of Resistive Lines

Ag Resistive Ink

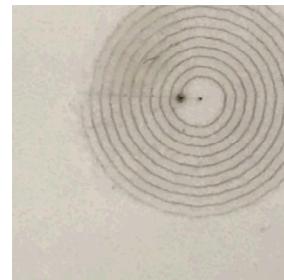
- Capacitors



Capacitors on Cylindrical Rod

Ag Pads, Polyimide Dielectric, Au Cylindrical Rod

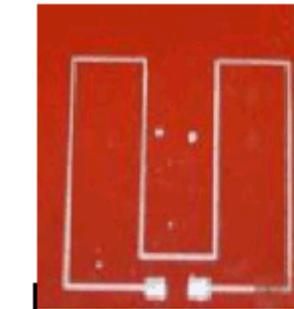
- Inductors



Spiral Inductor

Ag Ink

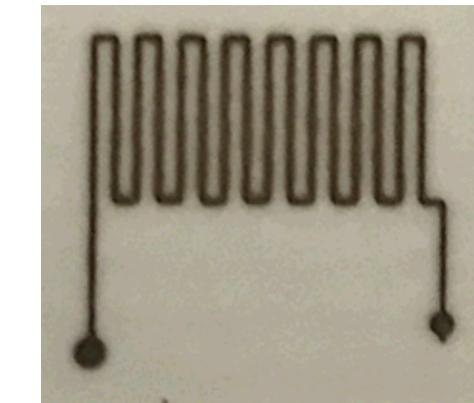
- Simple Strain Gauges



~ 5 cm

Ag Paste

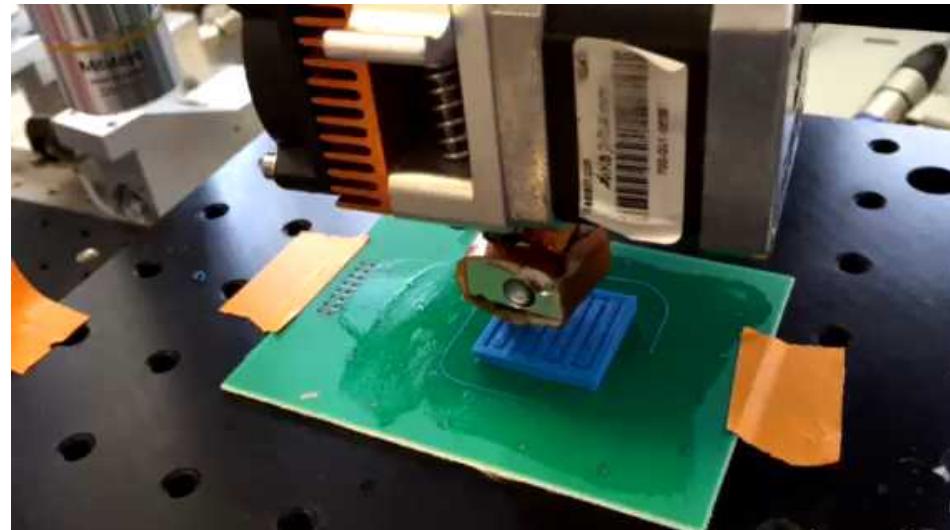
- Heating Elements



Ag Ink

Embedded AM Electronics

- Multi-Material Print Processes
 - Manufacturing of Both Structures and Electronics
- Multiple Machine Process
 - Part is Switched Between Machines Depending on Required Structure/Electronic Needs at a Given Point
- Methods of Embedding
 - Incorporated Tool-Paths



Sought Components

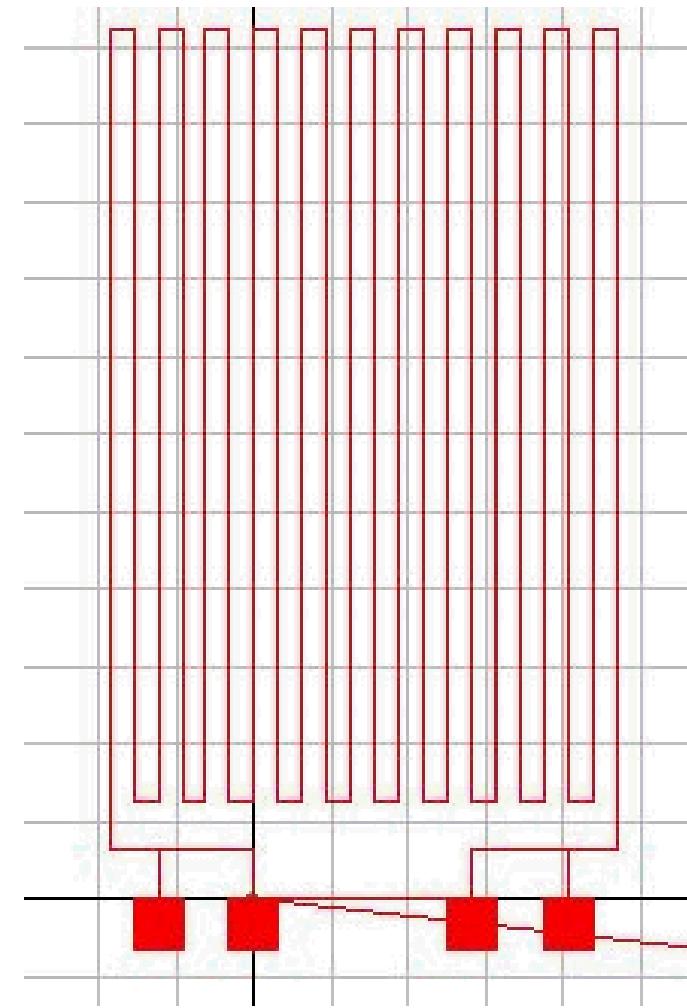
Strain Gauge

- *Measure Stress and Deflection of Component*
- Strain Causes Change in Cross-Sectional Area of Trace
 - Changes Resistance of Circuit
- Maximized Circuit Length
Accentuates Change in Resistance

Temperature Sensor

- *Measure Surface Temperature of Component*
- Coefficient of Thermal Resistivity Causes a Change in Resistance of the Circuit
- Maximized Circuit Length Accentuates Change in Resistance

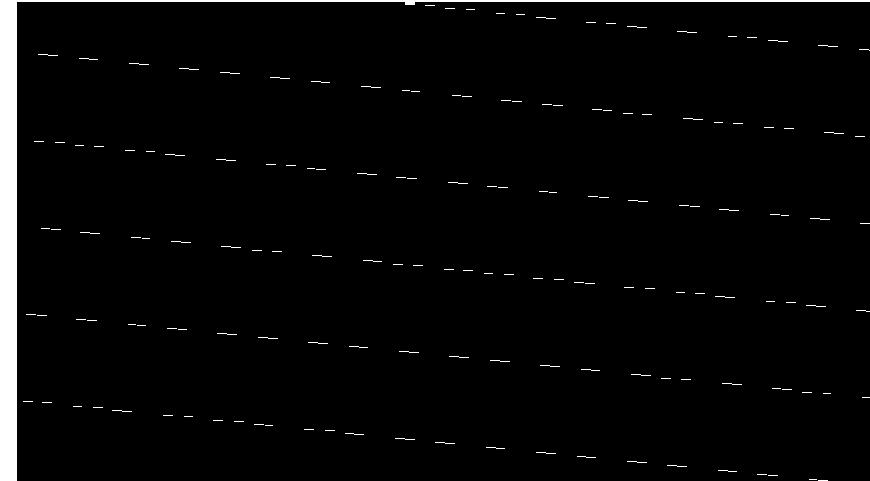
Component Design



Capabilities – Nanojet[©]



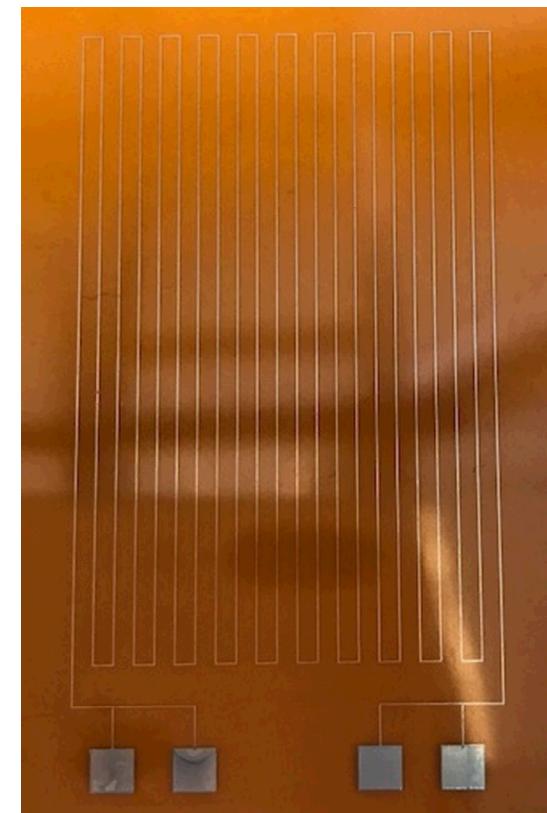
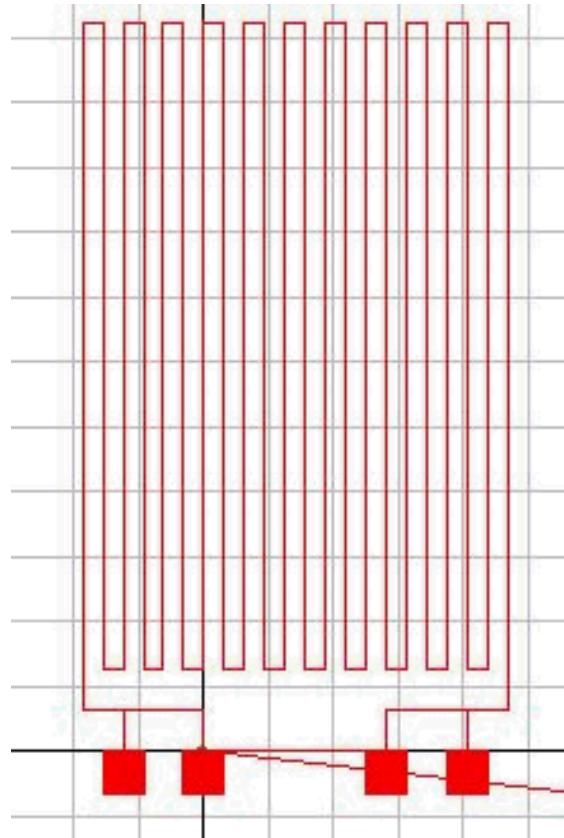
- Aerodynamic Focusing of Aerosolized Materials
 - Conductive Nanoparticle Inks
 - Dielectric Polymers
- Low Profile, Well Focused Traces
 - Trace Width From 50 to 300 μm
 - Single Layer Height of $\sim 1.5 \mu\text{m}$
- Parameters
 - Aerosol Flowrate
 - Sheath Gas Flowrate
 - Atomizer Voltage
 - Tip Height



Sensor Details

■ Prototype Print

- Deposited onto Kapton film
- Silver Nanoparticle Ink in Xylenes
 - Well Known Material Profile
 - Predictable Coefficient of Thermal Resistivity
- Test Component Printed Using Proven Technology (Aerosol Jet)
 - Sample Resistivity: $4.29\text{E-}8 \Omega\text{-m}$
 - Bulk Resistivity: $1.59\text{E-}8 \Omega\text{-m}$



Sensor Curing Profile

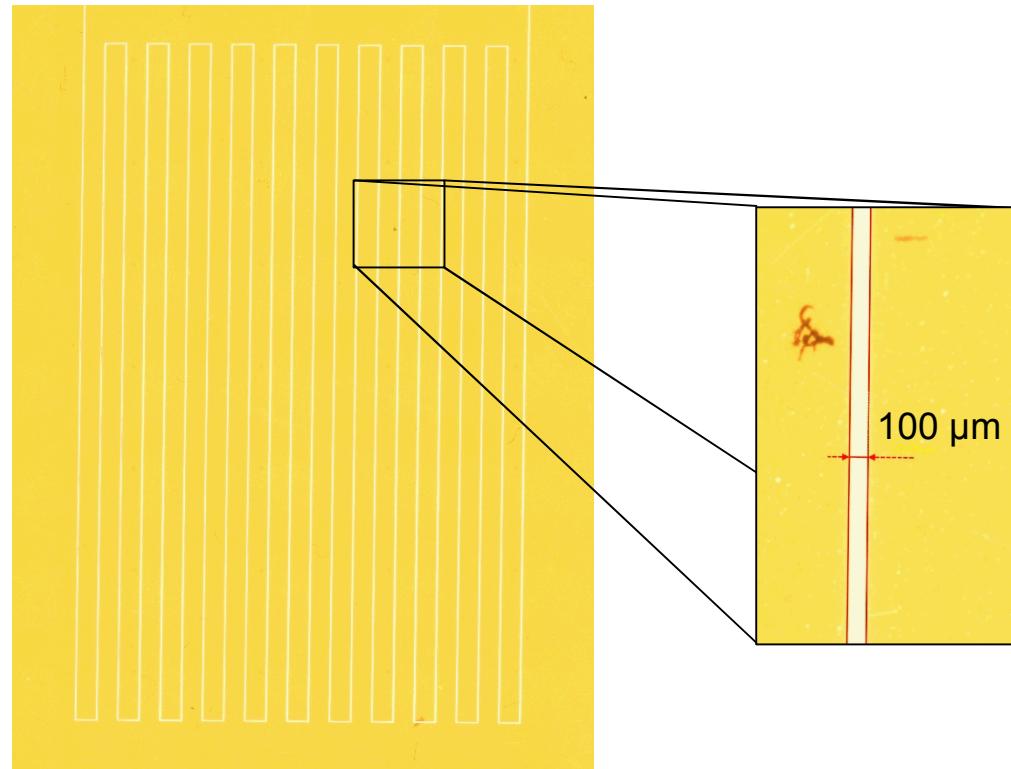
- Bulk Thermal Curing
 - Heated on hot plate at 170° C for 45 minutes

- Alternatives
 - Photonic Forge Curing
 - Low temperature
 - Short curing time commitment
 - Pulsed Laser Sintering
 - Accurate sintering of selected material

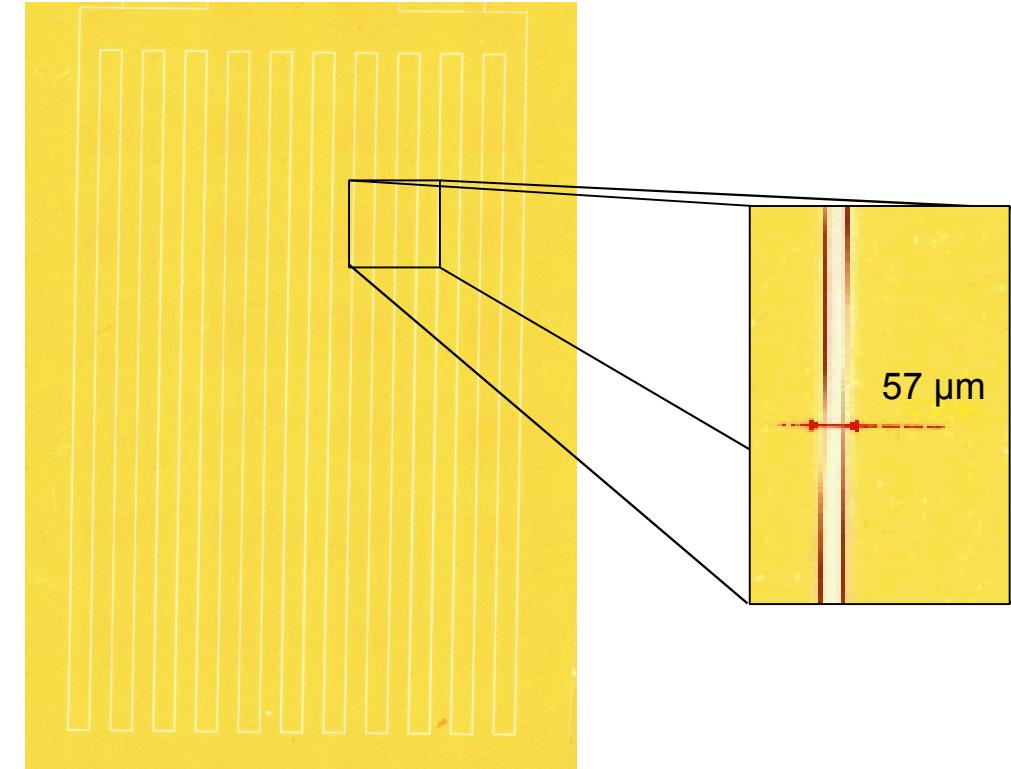


Effects of Curing

Before Curing

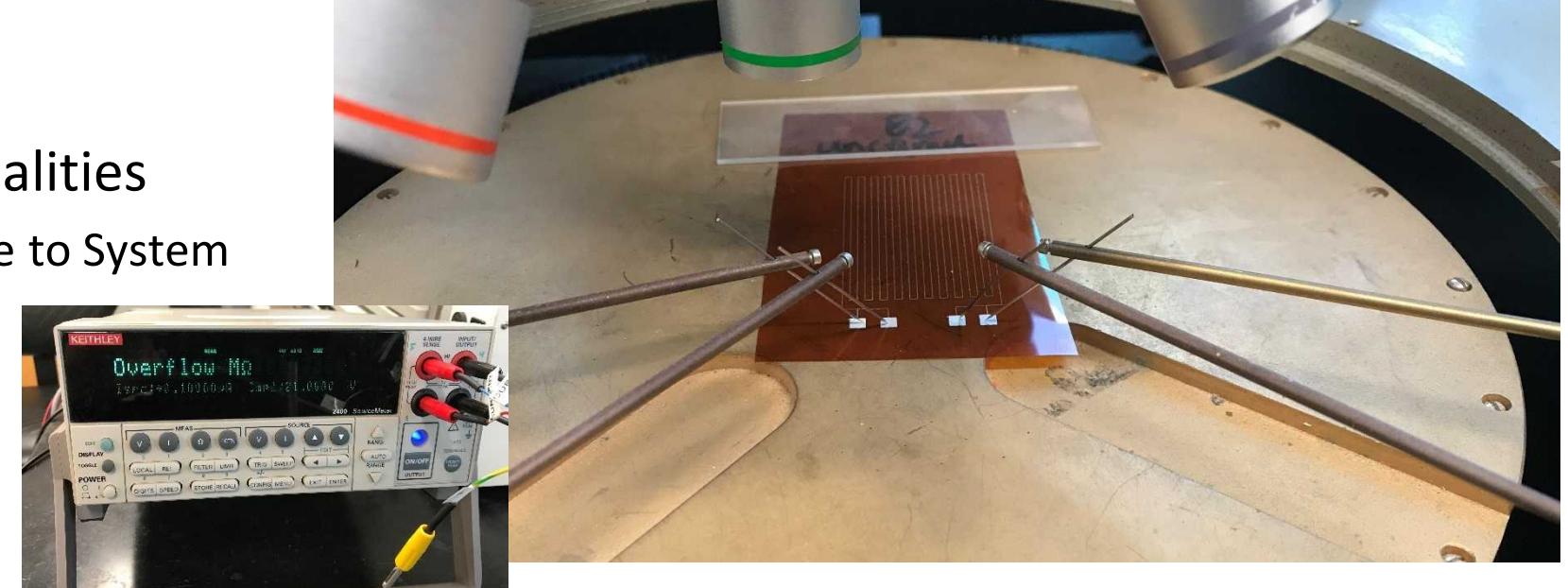


After Curing



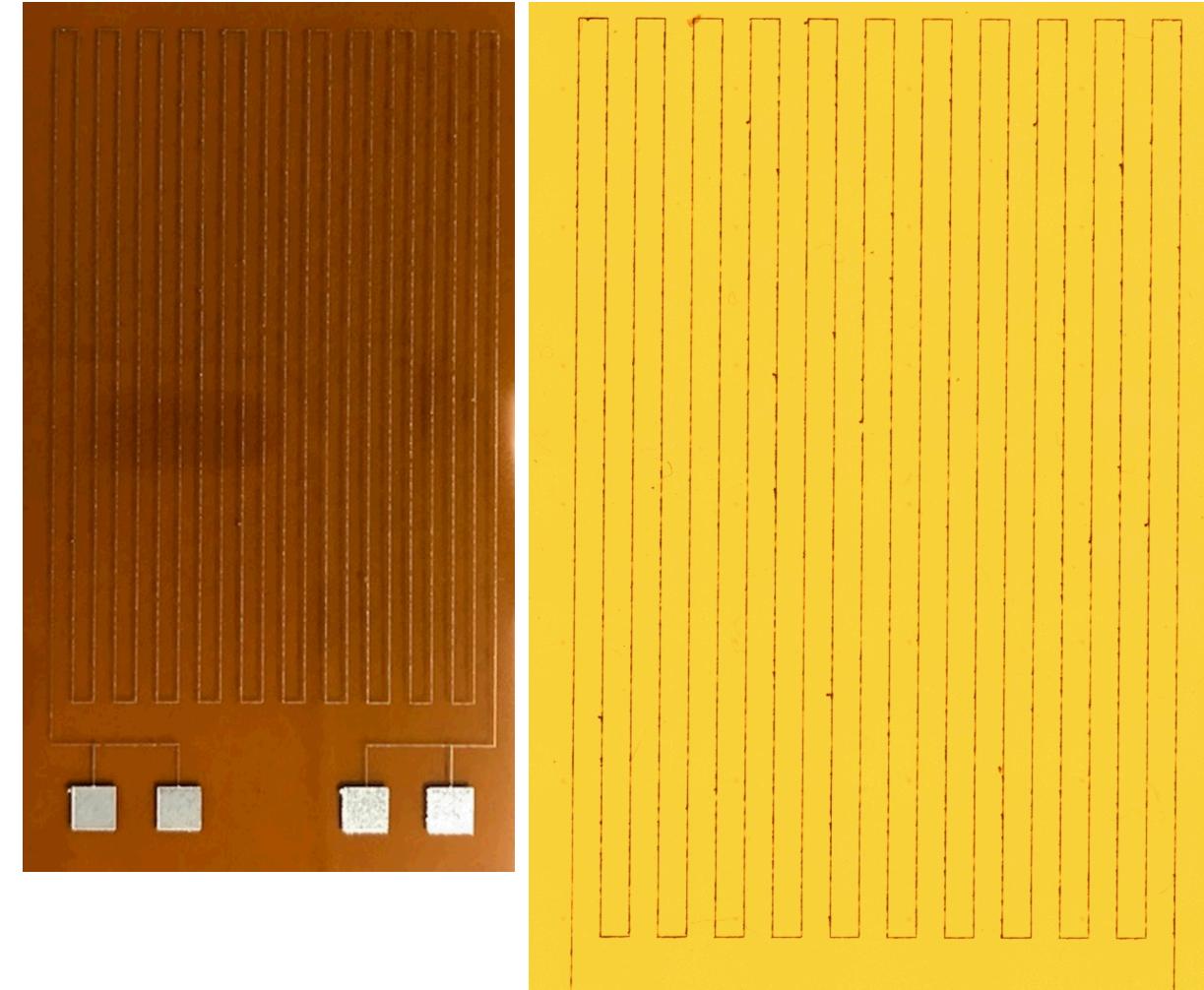
Printed Sensor Properties and Performance

- Issues Achieving Uniform, High-Quality Printed Sensors
- Issues Regarding Reliability in Circuit Continuity
- Lack of Continuity Prevented Measuring of Resistance and Calculating of Bulk-Resistivity
- Fragile Component Qualities
 - Testing Caused Damage to System

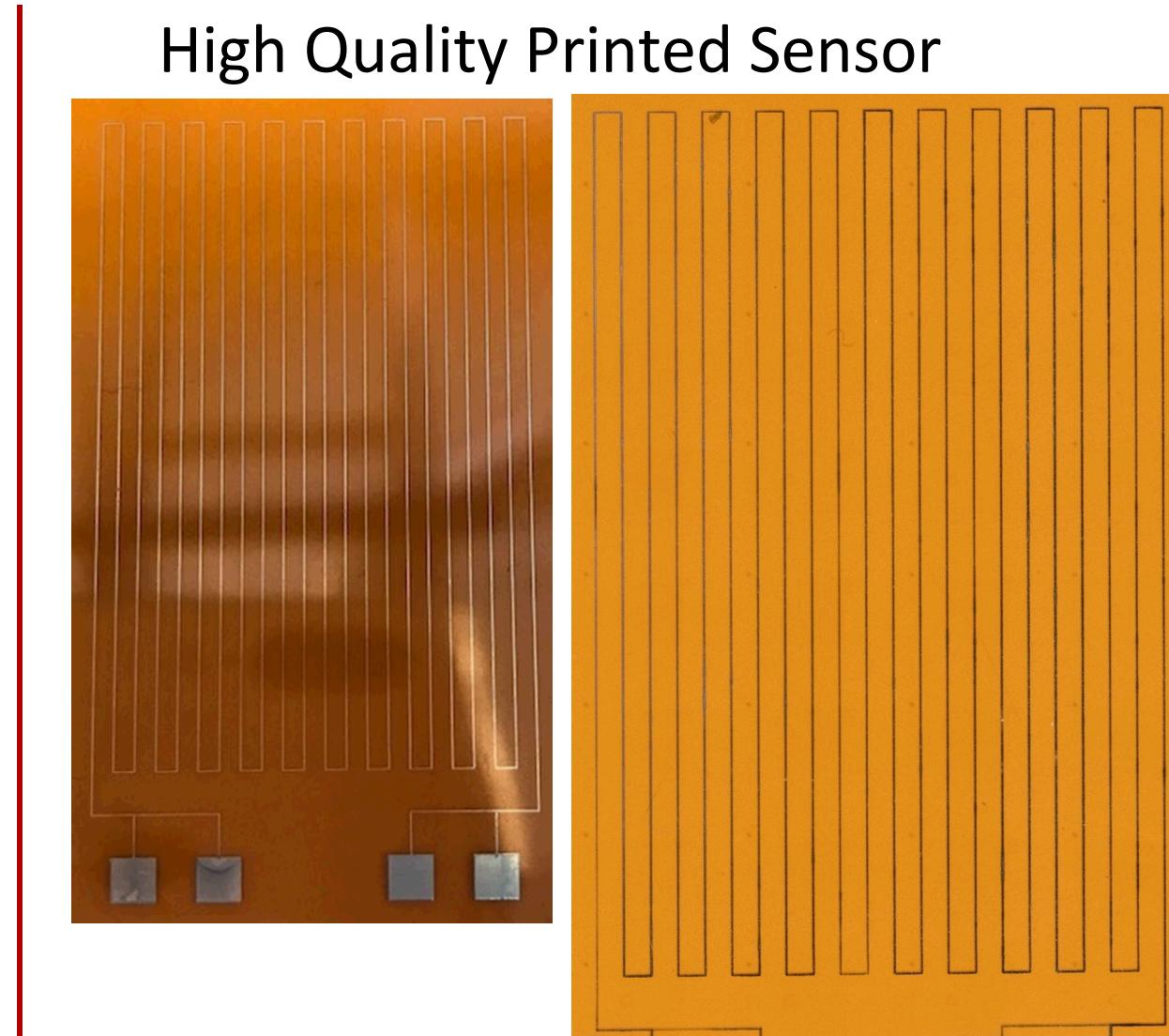


Sensor Properties and Performance (Cont.)

Poor Quality Printed Sensor



High Quality Printed Sensor



Reflection

- Extensive issues producing multiple usable samples proved to be a major stumbling block
 - Failure to establish repeatable print parameters
 - Prevented proper testing of components
- Possible sources of error include:
 - Coagulation of particles as ink aged
 - Inability to achieve accurate and precise tool height above substrate
 - Build up of material on nozzle as printing went on
 - Improper heating profile prevent sintering of particles

Future Steps

- Scale Stain Gauge Design to Sense in Multiple Axes
 - Insulating dielectric layer between serpentine paths
- Investigate the Production of Additively Manufactured Antennas
 - Wireless power transfer for passive electronics
 - RF sensors to remotely transmit information
 - Fracture detection
- Investigate Other Conductive Materials for More Adaptable Curing Profiles
 - Low Temperature curing materials
 - High Temperature curing materials
 - Non-temperature dependent curing materials
- Multiple Process Integration into Single Machine
 - Complete, Multi-material components in single print

Conclusion

- Continuing advancements in the Additive Manufacturing of both structure and electronics have created the opportunity to integrate the two into single vision
- Design of integrated components requires the consideration of both technology and material limitations
 - Material compatibility and curability require further investigation
- Further exploration is required into passive and remote components
- Eventual implantation of all-in-one systems to fully produce a finished, sensing part

THANK YOU!

POCKET SLIDES/QUESTIONABLE WORK IN PROGRESS SLIDES

Long Term Goals

- Embedded Health Monitoring
 - Stress monitoring
 - Temperature monitoring
- Passive Electrical Components
 - No need for incorporated batteries or power banks
- Remote Communication with Sensors
- Single Process Prints
 - One machine to build both structures and embedded electronics

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Complication – Material Compatibility



- Solvents Used to Suspend Nanoparticles Can Damage Substrate
 - Xylenes corrode plastics
- Non-uniform Wetting of Aerosols onto Different Materials
- Profilometry and picture of substrate that has had suspending solvent eat through it
 - Profilometry should have a valley along the trace

Solution – Material Compatibility

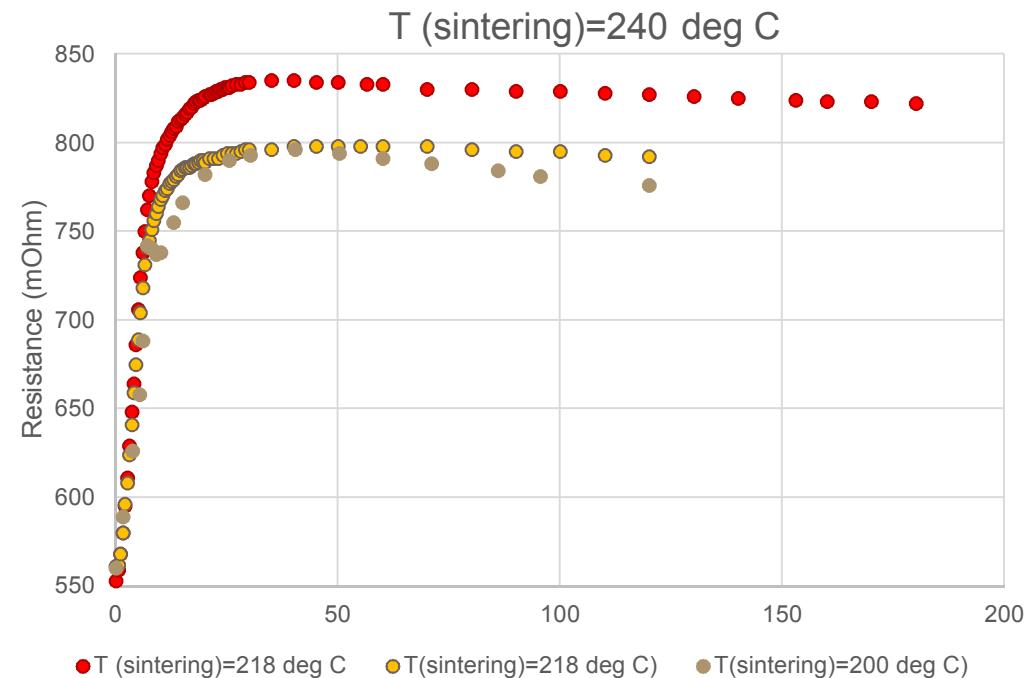


- Substitution of solvent for less aggressive solvent
 - Requires large inventory to ensure compatibility across all materials
- Printing of a protective dielectric between substrate and trace
- Picture of protective-layer print

Complication – Curing Compatibility

- Traces cure between 50 C and 200 C for ~1 hour
 - Plastics begin to flow at about 70 C
 - Ceramics cure at XXXXX C for XXXXX hours

- Show melted substrate w/ cured trace
 - ABS
- Show burned trace on cured substrate
 - Alumina

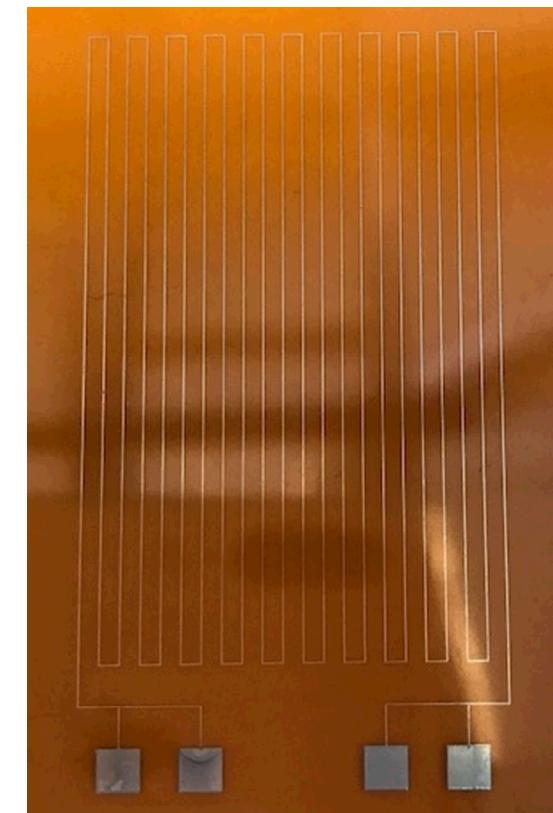
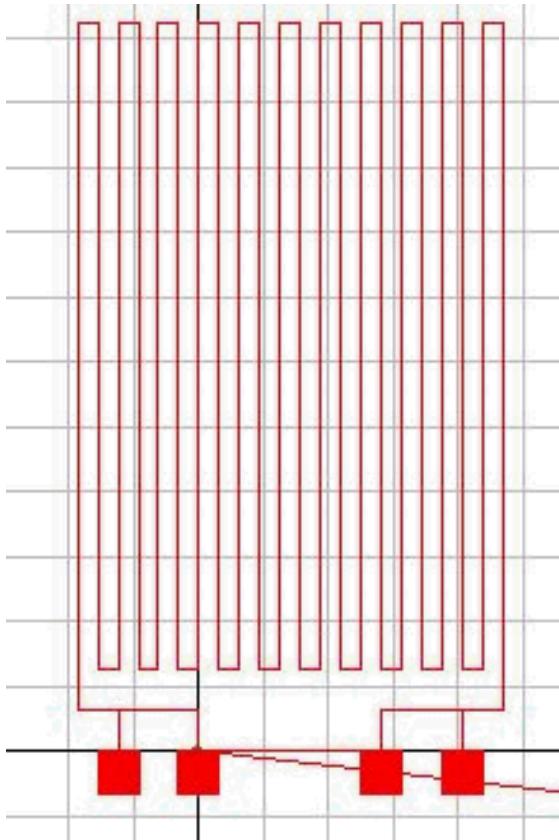


Interest in Embedded Electronics

- Embedding Electronics and Sensors Allows Them to be Placed at Critical Points
 - Not Limited To Available Surface Space
- Strain Gauges
 - Measure Stress and Deflection of Component
- Temperature Sensors
 - Measure Surface Temperature of Component
- Uses
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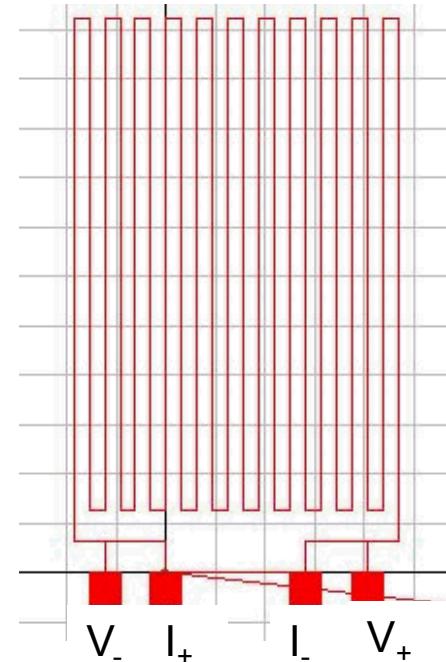
Sensor Details

- Design
 - Serpentine Trace
 - Maximizes length in a given area
 - Four Contact Pads
 - 4-point terminal sensing
- Prototype Print
 - Deposited onto Kapton film
 - Silver nanoparticle ink in Xylenes
 - Well known material profile
 - Predictable Coefficient of Thermal Resistivity
 - Test Component Printed Using Proven Technology (Aerosol Jet)
 - Resistivity: $2.05\text{E-}7 \Omega\text{-m}$



Testing Conditions

- 4-Point Probing
 - Supply Constant Current and Voltage to Component
 - Provides Stable and Accurate Resistance Reading
- Cross-Sectional Area Measured Through Profilometry of Sensor
- Sensor Dimensions Used to Calculate Bulk-Resistivity of Material



$$\blacksquare R = \frac{\rho L}{A}$$

References

- Lazar, Miriam. *Lets Review: Physics, the Physical Setting*. Third edition. United States: Barrons, 2007: 217.